# Application/Control No. 09/775,760 Examiner Devesh Khare Applicant(s)/Patent Under Reexamination MALLON ET AL. Art Unit Page 1 of 1

## Notice of References Cited

#### **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-3,835,006	09-1974	Fujita et al.	204/180
	ø	US-4,246,092	01-1981	Perry et al.	204/301
	U	US-6,482,940	11-2002	Klohr et al.	536/84
	٥	US-2002/0016452	02-2002	Obara et al.	536/88
	E	US-2002/0168407	11-2002	Koch et al.	424/480
	ŀ	US-			
	G	US-			
	н	US-			
	1	US-			
	J	US-			
	κ	US-			
	Ľ	US-			
	М	US-			

#### **FOREIGN PATENT DOCUMENTS**

	·							
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification		
*	N.	DE 16 68 347	09-1971	Germany	Warzecha et al.	-		
*	0	JP 01-149801	06-1989	Japan	Takahashi et al.	-		
	Р							
	Q							
	R							
	s			-				
	T					·		

### NON-PATENT DOCUMENTS

$\overline{}$						
*	<u> </u>	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	v					
	w					
	х					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

U.S. Patent and Trademark Office PTO-892 (Rev. 01-2001)